

# **FPN330** FPN330A



## **NPN Low Saturation Transistor**

These devices are designed for high current gain and low saturation voltage with collector currents up to 3.0 A continuous. Sourced from Process NB.

#### **Absolute Maximum Ratings\*** TA = 25°C unless otherwise noted

Symbol	Parameter	Value	Units	
$V_{CEO}$	Collector-Emitter Voltage	30	V	
V <sub>CBO</sub>	Collector-Base Voltage	50	V	
V <sub>EBO</sub>	Emitter-Base Voltage	5.0	V	
I <sub>C</sub>	Collector Current - Continuous	3.0	А	
T <sub>J</sub> , T <sub>stg</sub>	Operating and Storage Junction Temperature Range	-55 to +150	°C	

<sup>\*</sup>These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

NOTES:

1) These ratings are based on a maximum junction temperature of 150 degrees C.

2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

#### **Thermal Characteristics** TA = 25°C unless otherwise noted

Symbol	Characteristic	Max	Units	
		FPN330 / FPN330A		
P <sub>D</sub>	Total Device Dissipation	1.0	W	
R <sub>θ</sub> JC	Thermal Resistance, Junction to Case	50	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	125	°C/W	

## **NPN Low Saturation Transistor**

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TA = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Max	Units
OFF CHA	OFF CHARACTERISTICS				
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$BV_{CEO}$	Collector-Emitter Breakdown Voltage	$I_C = 10 \text{ mA}, I_B = 0$	30		V
BV <sub>CBO</sub>	Collector-Base Breakdown Voltage	$I_C = 100  \mu A,  I_E = 0$	50		V
BV <sub>EBO</sub>	Emitter-Base Breakdown Voltage	$I_E = 100  \mu A,  I_C = 0$	5.0		V
I <sub>CBO</sub>	Collector Cutoff Current	$V_{CB} = 30 \text{ V}, I_{E} = 0$		100	nA
		$V_{CB} = 30 \text{ V}, I_{E} = 0, T_{A} = 100^{\circ}\text{C}$		10	μΑ
I <sub>EBO</sub>	Emitter Cutoff Current	$V_{EB} = 4.0 \text{ V}, I_{C} = 0$		100	nA

## ON CHARACTERISTICS\*

h <sub>FE</sub>	DC Current Gain	$I_C = 100 \text{ mA}, V_{CE} = 2.0 \text{ V}$	330	100		
			330A	250		
		$I_C = 1.0 \text{ A}, V_{CE} = 2.0 \text{ V}$		120		
		$I_C = 2.0 \text{ A}, V_{CE} = 2.0 \text{ V}$		50		
V <sub>CE(sat)</sub>	Collector-Emitter Saturation Voltage	$I_C = 1.0 \text{ A}, I_B = 100 \text{ mA}$	330		500	mV
- ( )			330A		450	mV
		$I_C = 2.0 \text{ A}, I_B = 200 \text{ mA}$			1.0	V
V <sub>BE(sat)</sub>	Base-Emitter Saturation Voltage	$I_C = 1.0 \text{ A}, I_B = 100 \text{ mA}$			1.25	V
V <sub>BE(on)</sub>	Base-Emitter Saturation Voltage	$I_C = 1.0 \text{ A}, V_{CE} = 2.0 \text{ V}$			1.0	V

## SMALL SIGNAL CHARACTERISTICS

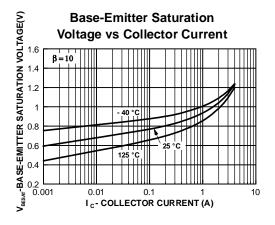
C <sub>obo</sub>	Output Capacitance	$V_{CB} = 10 \text{ V}, I_E = 0, f = 1.0 \text{ MHz}$		30	pF
F <sub>T</sub>	Transition Frequency	$I_C = 100 \text{ mA}, V_{CE} = 5.0 \text{ V},$ f = 100  MHz	100		MHz

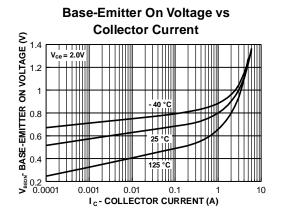
<sup>\*</sup>Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2.0%

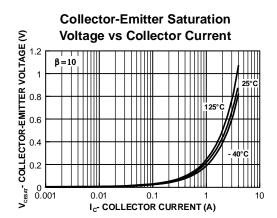
## **NPN Low Saturation Transistor**

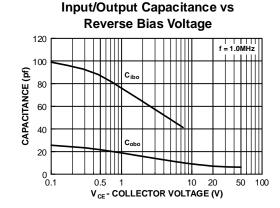
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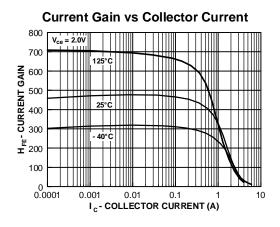
## **Typical Characteristics**

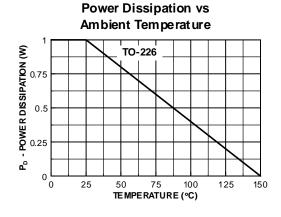












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